

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/815,640	LAPSTUN ET AL.	
Examiner	Art Unit	
Madeleine AV Nguyen	2625	

SEARCHED				
Class	Subclass	Date	Examiner	
update		3/28/2006	AV	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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